

20/11/2025



FOCH Project

**Development of a fault-tolerant IP
and evaluation of FPGA SRAM with tests in
a highly radiative environment**

TABLE RONDE

FOCH Presentation



ALP KILIC

NanoXplore



**FLORENT
MILLER**

Nuclétudes



**ALEJANDRO
URENA-ACUNA**

Radiation engineer at ONERA



**JOSEPH
PATUREL**

INRIA



20/11/2025
9h20-9h50

REFECTOIR
RE

FOCH global Presentation

20/11/2025
9h20-9h50

—
Refectoire



Alp KILIC

NanoXplore



**Development of a fault-
tolerant IP and evaluation of FPGA
SRAM with tests in a highly radiative
environment**

FOCH_A 100% French
project

Project presentation

Coordinator



NX Subcontractor



2 french partners



Beginning of the project: 06/2024

End of the project: 09/2027 (36 months)

Funding: DGA



Project presentation

Manufacturing issues and process variations strongly affects the electrical parameter of circuits and architectures, leading to a significant reduction in manufacturing yields.

Transient errors caused by particles or radiation occur more frequently during operation, and process variability will prevent accurate prediction of chip performance.

Many systems are constantly under attack from intruders, and security has become of utmost importance.



Main objectives :

1. Evaluate NX FPGA SRAM technology linked to heavy radiative environments (such as aeronautical environments, launchers and defense environments).
2. Develop a RISC-V fault-tolerant IP.
3. Compare the analysis performed under particle beams or by laser injection. RISC-V processor validation and qualification.
4. Compare the sensitivity and performance of RISC-V processor IP carried on the NX FPGA target and on a state-of-the-art commercial FPGA target.



European Leader in FPGA, Soc FPGA & ASIC Design

- ✓ French Based Company : Paris, Montpellier, Grenoble
- ✓ 140+ Employees with more than 90% R&D Engineers
- ✓ Offer products for Hi-Rel markets
- ✓ 3 different products offering :
 - High reliable SoC FPGA
 - ASIC design services
 - Silicon IPs
- ✓ ITAR Free Technology
- ✓ Focus on Space & Defense markets



Products Overview

NG medium

Low-End FPGA

35kLUTs/32kDFFs

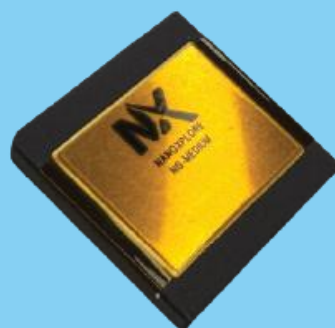
2.6Mb RAM

112 DSP

SpaceWire PHY

High Level SEU Rate

- Companion chip



ESCC9000 qualified

ultra300

Mid-End FPGA

290kLUTs/273kDFFs

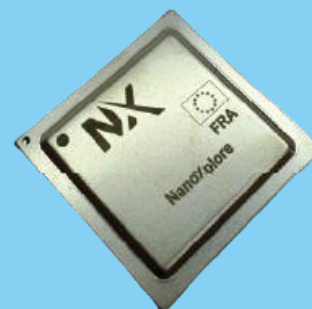
21Mb RAM

896 DSP

16x HSSL 12G

ADC/DAC

- Payload
- Platform
- Sensor control
- Power control loop



ESCC9030 expected

NG ultra

High-End FPGA

537kLUTs/505kDFFs

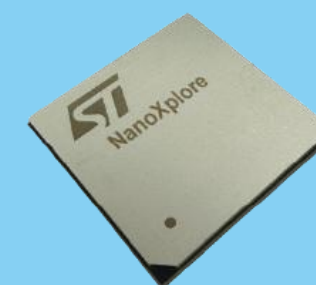
32Mb RAM

1344 DSP

32x HSSL 12G

Quad-core ARM-R52 (SoC)

- Payload
- Platform

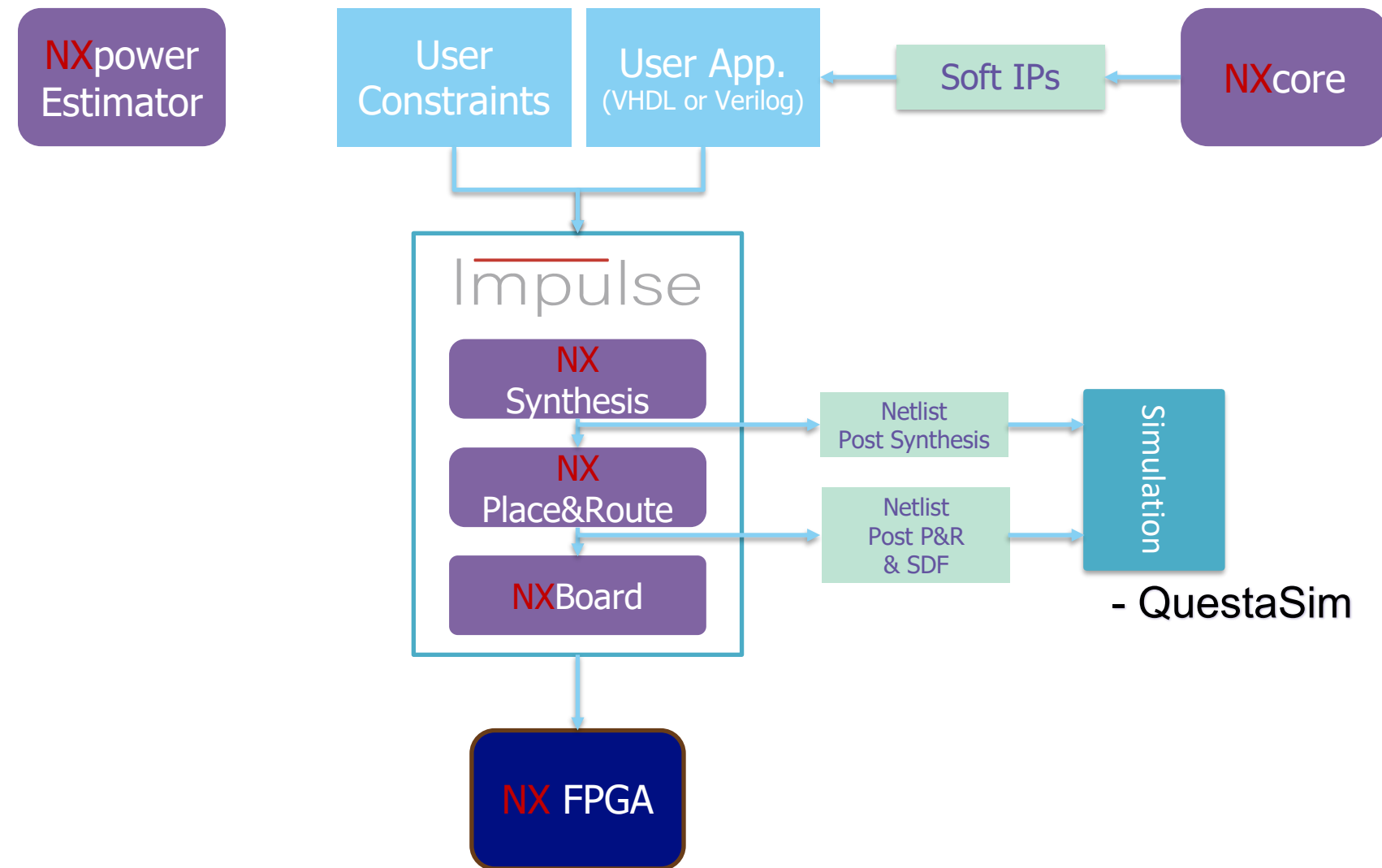


ESCC9030 expected

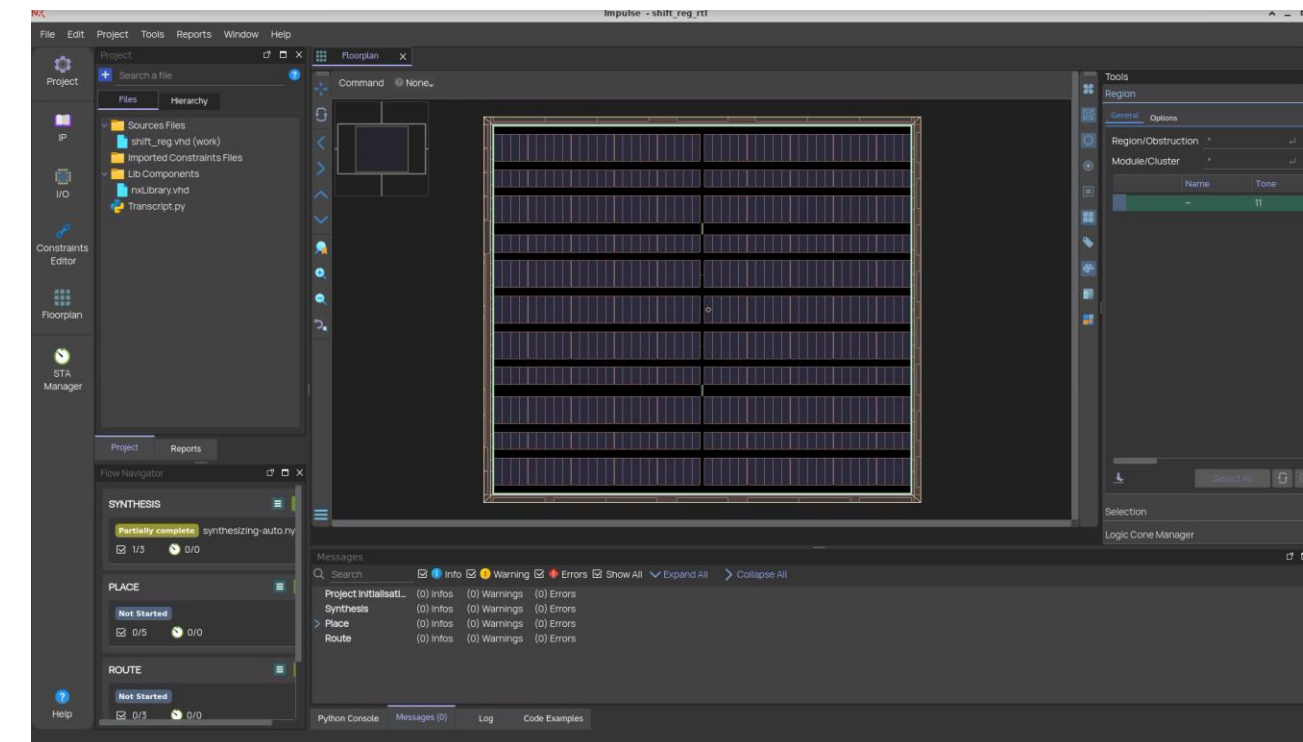
65 nm

28 nm

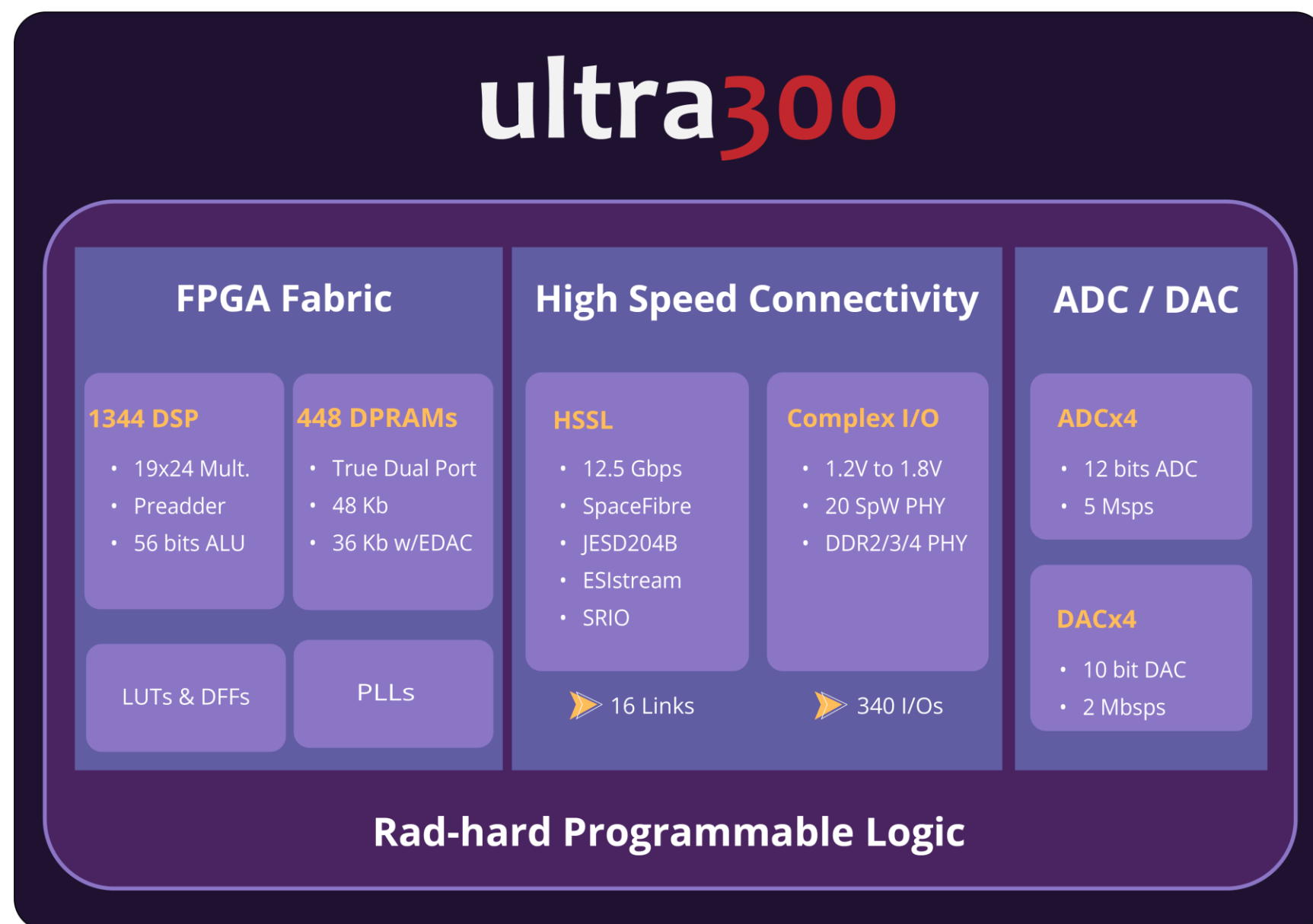
Impulse FPGA Flow



- : User input
- : NX Software
- : 3rd party Software
- : Output file



ULTRA300 Rad Hard



- All-rounder
 - ✓ Small form factor with FCBGA-484
 - ✓ High pin count with FCBGA-1152
- Benefits from NG-ULTRA experience
 - ✓ FPGA Fabric
 - ✓ High Speed Connectivity
 - ✓ Radiation Performance*
 - ✓ Ecosystem
 - ✓ ... and more

* Configuration Memory: 0 errors up to LET 62 MeV*cm²/mg



FOCH global Presentation

20/11/2025
9h20-9h50

Refectoire



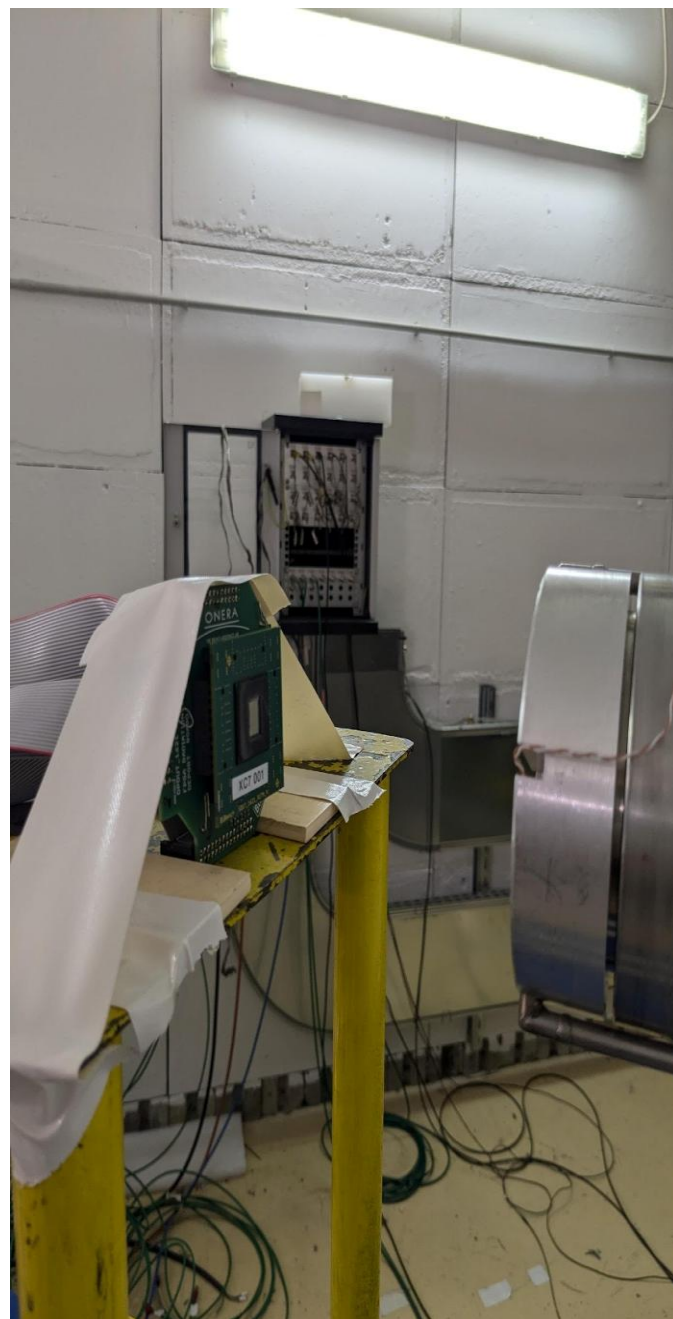
Alejandro
URENA-
ACUNA

ONERA



**Development of a fault-
tolerant IP and evaluation of FPGA
SRAM with tests in a highly radiative
environment**

ONERA ECM team



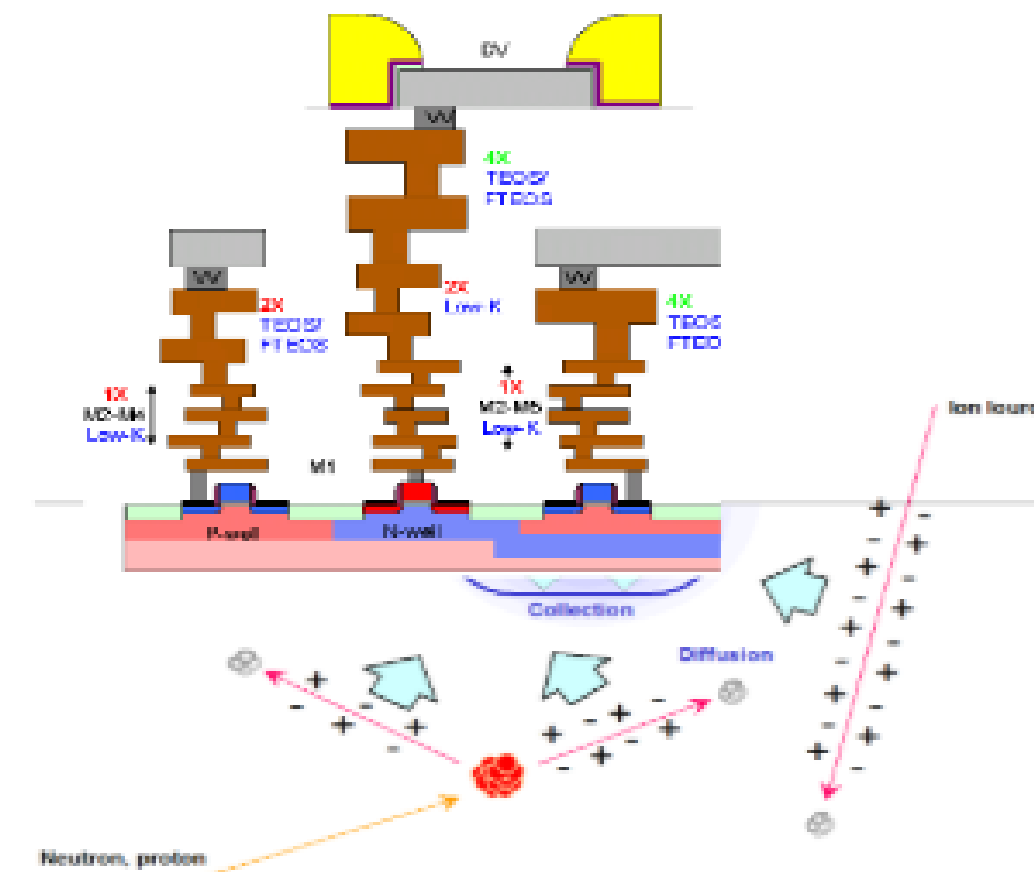
Experimental evaluation of COTS and ASICs

ECM team composed of:

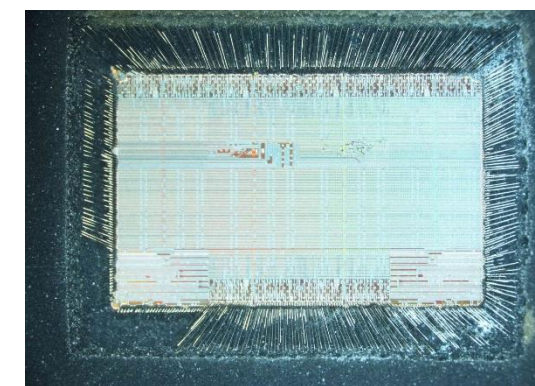
- 13 Permanents
- 10 Phd students
- 1 post-doc

Main activities:

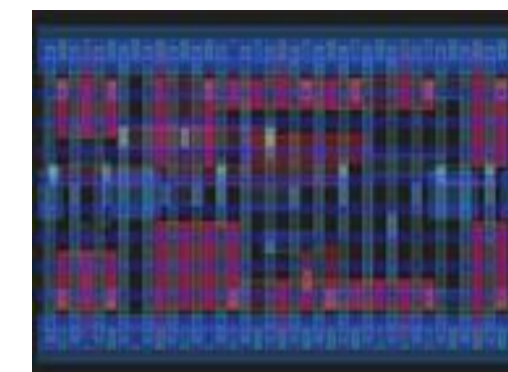
- Radiation effects in materials and microelectronics devices
- Strong experience in diagnosing radiation response of COTS and ASICs through experimental and simulation means by using the fault injection technique (MUSCA SEP3 + TERRIFIC)
- SEE characterization in deep technological nodes (ex. 65 nm bulk , 7nm FinFET, 28nm FDSOI)



Particle-Semiconductor interaction

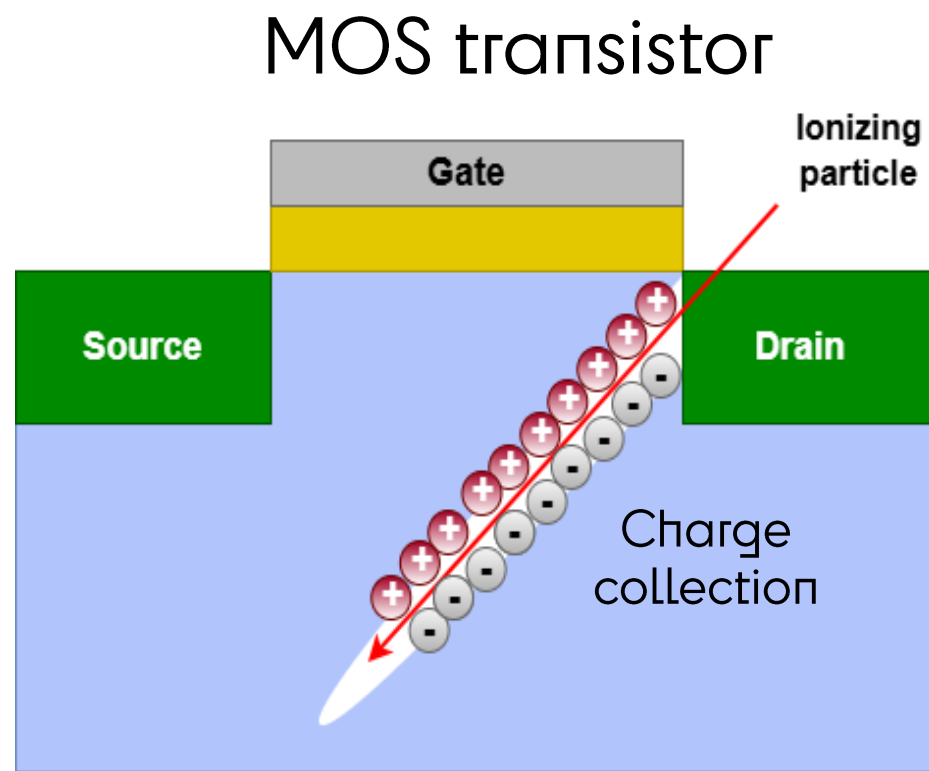


Top view of an ASIC

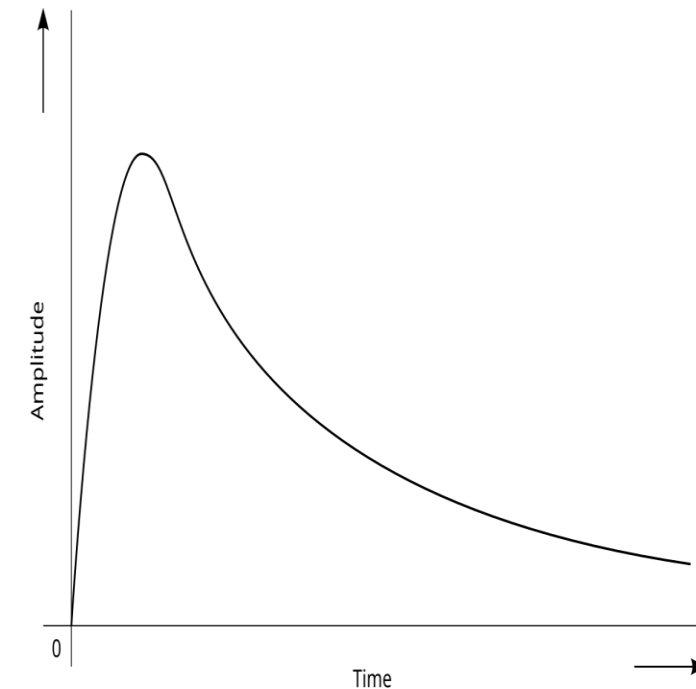


Circuit layout

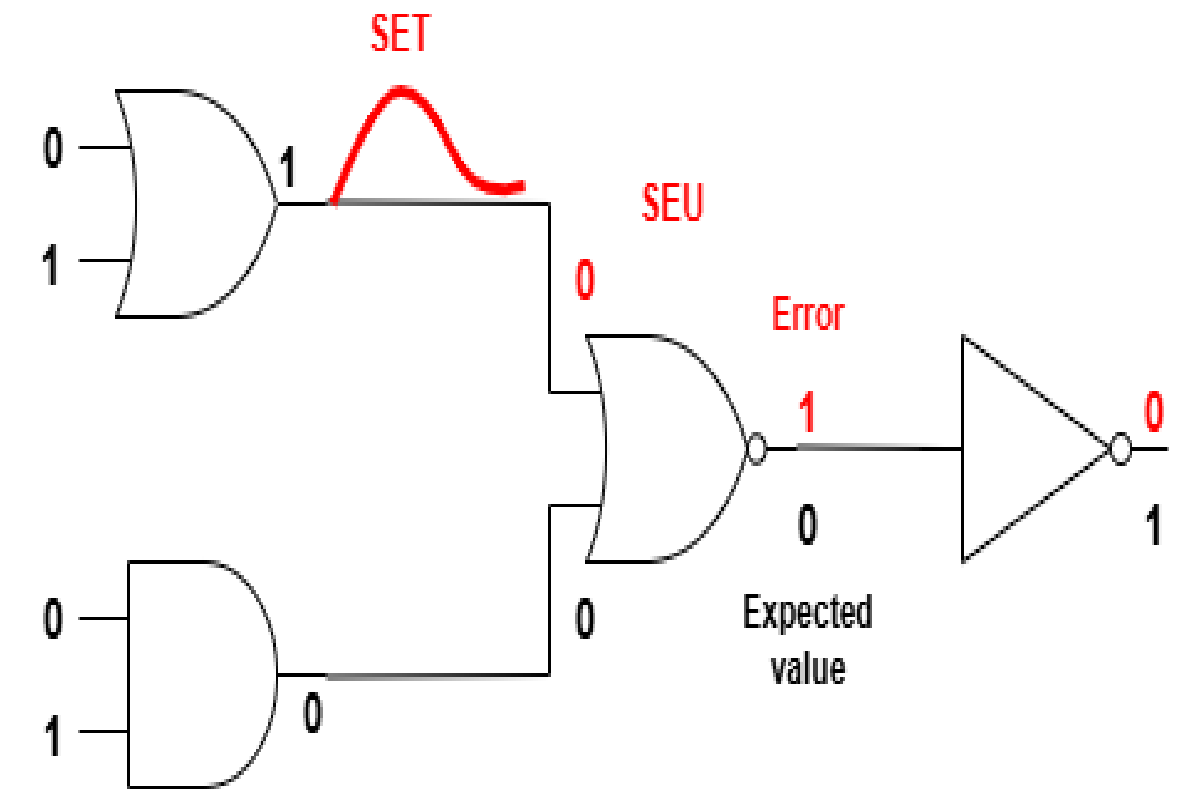
Introduction: Radiation effects in electronics



Bulk, SOI, FinFET



Single event transients (SET's)



Errors in combinational and sequential logic

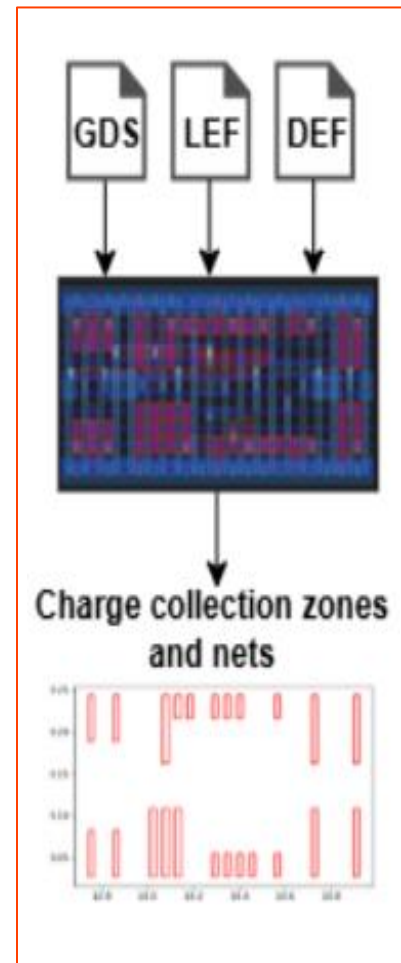
Scope of ONERA

SEE {
Single event transients (SET)
Single event upset (SEU)
Multiple event upset (MBU)

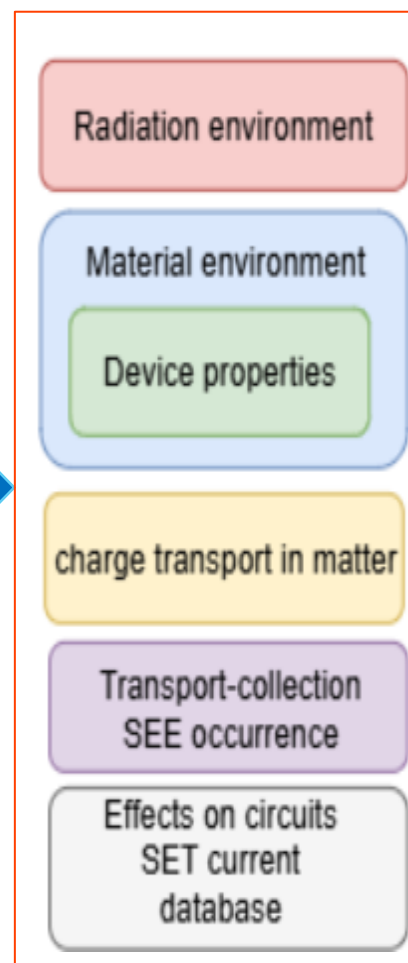
Multiple cell upsets (MCU)

ONERA Simulation flow: MUSCA SEP3 + TERRIFIC

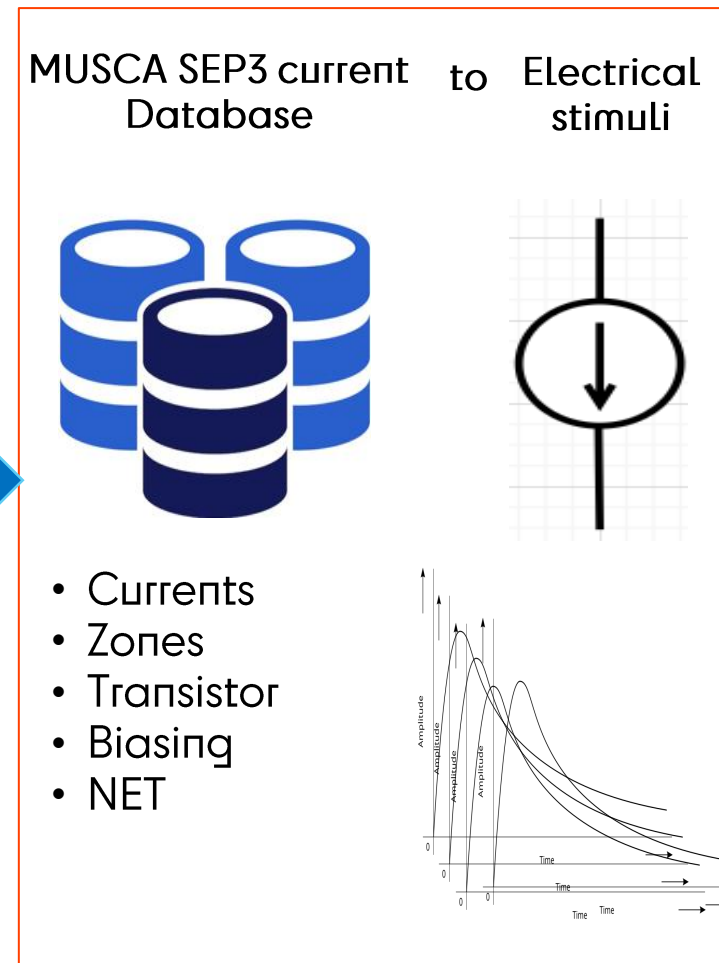
Circuit analysis



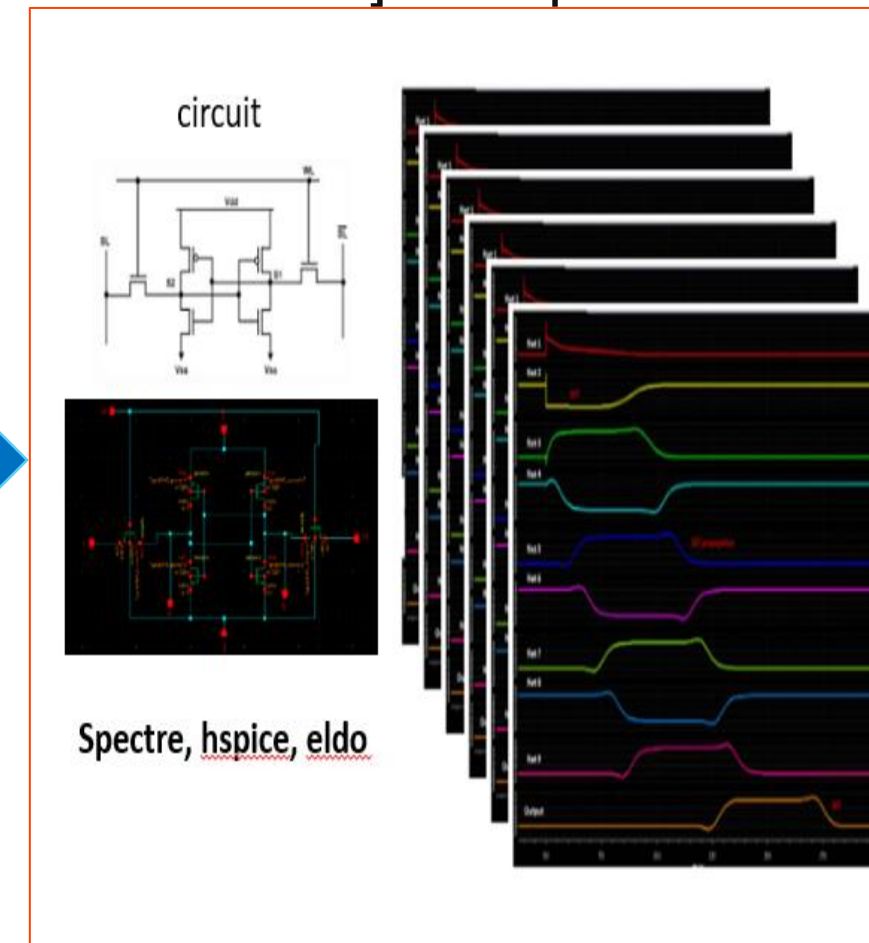
MUSCA SEP3



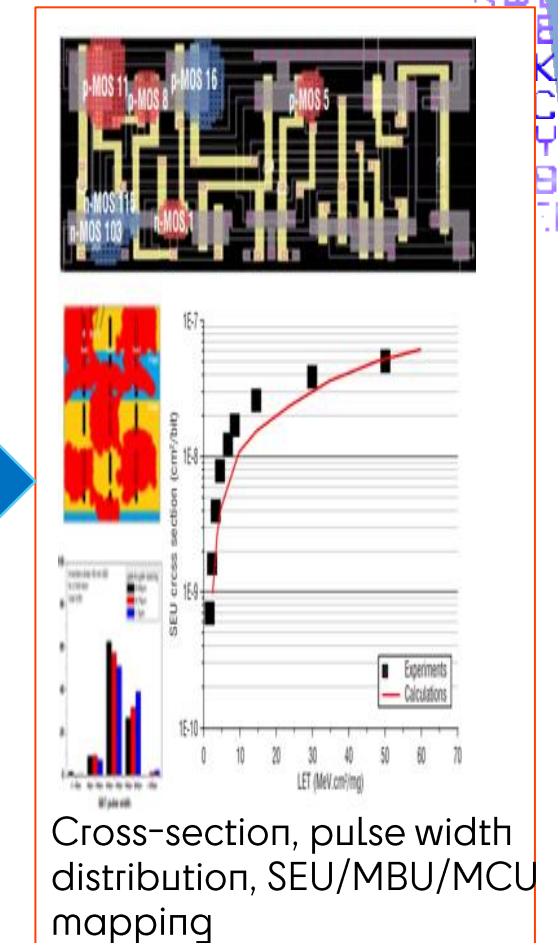
Stimuli generation



TERRIFIC :
Fault injection platform



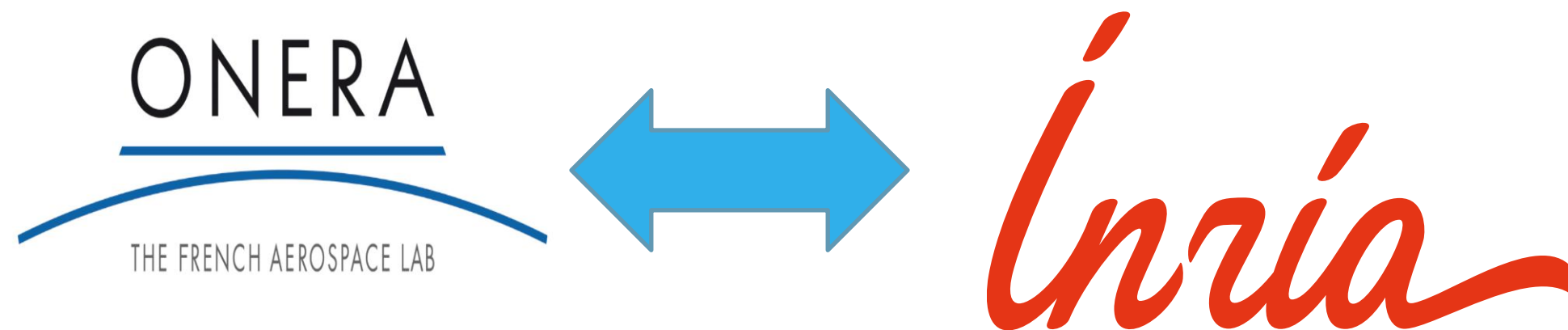
Post-processing



The MUSCA SEP3 coupled with TERRIFIC simulation flow is also effective in determining MBUs and MCUs in deep technological nodes: ex. 7nm FinFET

ONERA's goals in FOCH Project

- Evaluation of Nanoplore digital cells with the MUSCA SEP3 and TERRIFIC simulation tools.
- Generation of an SET current database through MUSCA SEP3
- Simulation of the radiation response digital blocks such as the configuration memory, DFFs, and LUTs
- Definition of a fault injection formalism with INRIA for an RTL-level fault test



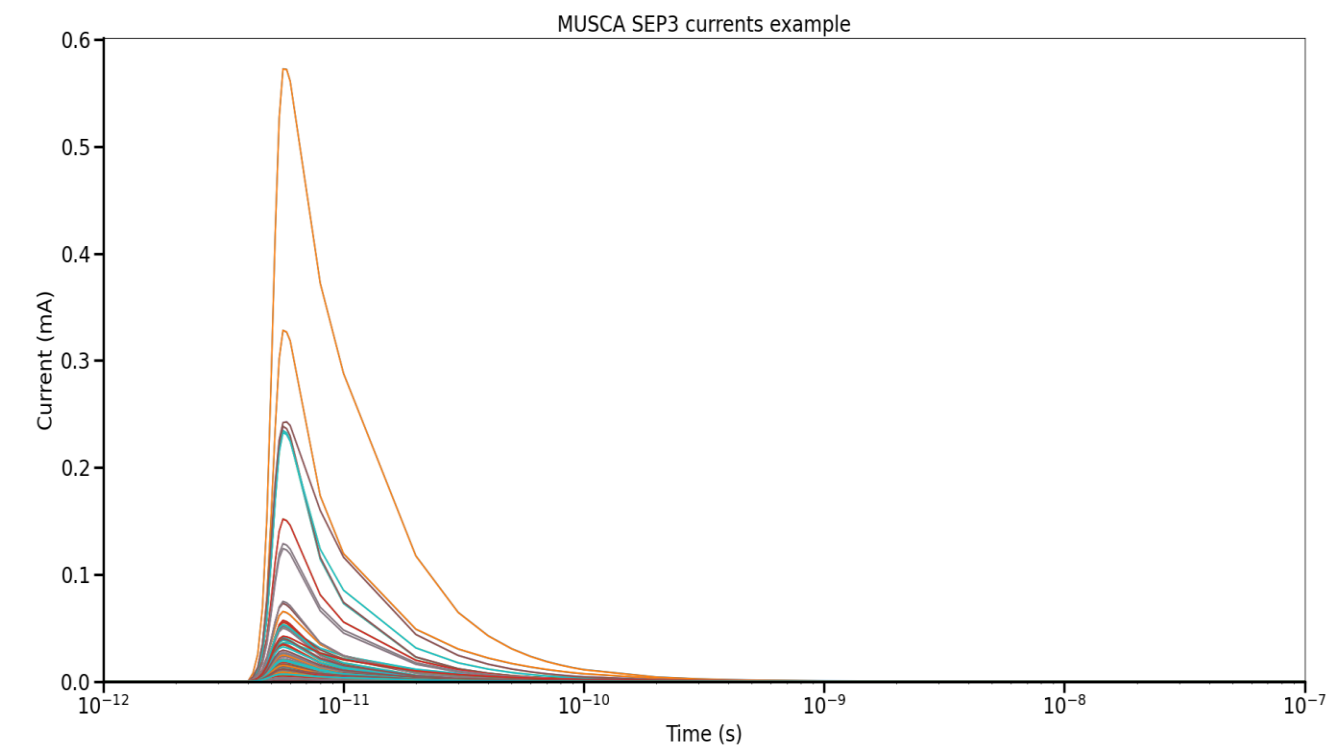
First results of ONERA SEE evaluation for FOCH

Evaluation of Nanoplore digital blocks:

- Configuration memory
- DFFs
- LUTs

Results and first conclusions

- No errors observed under a 23 MeV neutrons SET database
- Confirms the Nanoplore FPGA robustness
- New databases will be generated including protons and heavy ions in order to test the FPGA robustness
- Need of experimental data to confirm the obtained results



Examples of MUSCA SEP3 generated SETs

FOCH global Presentation

20/11/2025
9h20-9h50

—
Refectoire



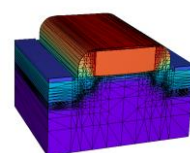
**FLORENT
MILLER**

Nuclétudes



**Development of a fault-
tolerant IP and evaluation of FPGA
SRAM with tests in a highly radiative
environment**

NUCLETUDES IN THIS CONSORTIUM



Task-1

Multi-layer analysis by simulation of the fault tolerance of the NX target FPGA



Task-2

Experimental characterization of the fault tolerance of a RISC-V IP implemented on two different FPGA targets



- Design elementary tests
- Prepare fault injection
- Perform experiment
- Analyze results



Task-3

Implementation of hardening strategies on the RISC-V IP



- Knowledge in hardening strat.
- Knowledge in RISC-V IP archi.
- Complementary tests (ex: laser)
- Analyze fault injection

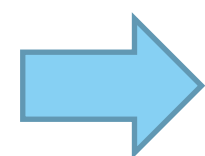


Task-4

Experimental validation of the benefit of the implemented hardening strategies on the RISC-V IP



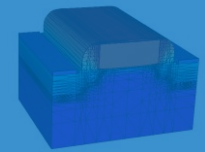
- Design elementary tests
- Prepare fault injection
- Perform experiment
- Analyze results



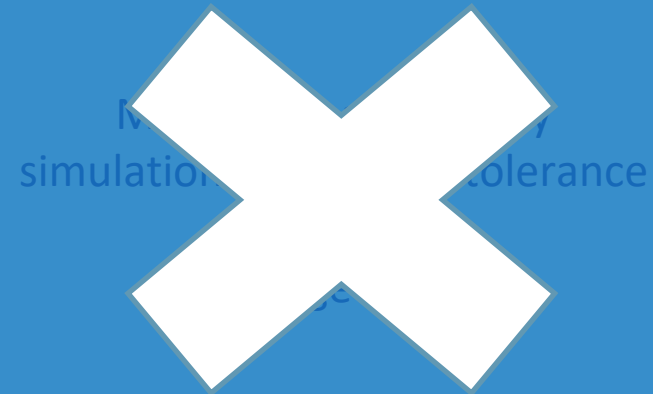
As expert in radiation experiments with a strong knowledge on testing complex components



NUCLETUDES IN THIS CONSORTIUM



Task-1

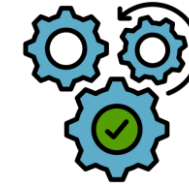


Task-2

Experimental characterization of the fault tolerance of a RISC-V IP implemented on two different FPGA targets



- Design elementary tests
- Prepare fault injection
- Perform experiment
- Analyze results



Task-3

Implementation of hardening strategies on the RISC-V IP



- Knowledge in hardening strat.
- Knowledge in RISC-V IP archi.
- Complementary tests (ex: laser)
- Analyze fault injection results

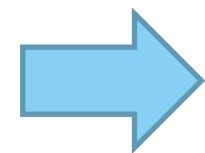


Task-4

Experimental validation of the benefit of the implemented hardening strategies on the RISC-V IP



- Design elementary tests
- Prepare fault injection
- Perform experiment
- Analyze results

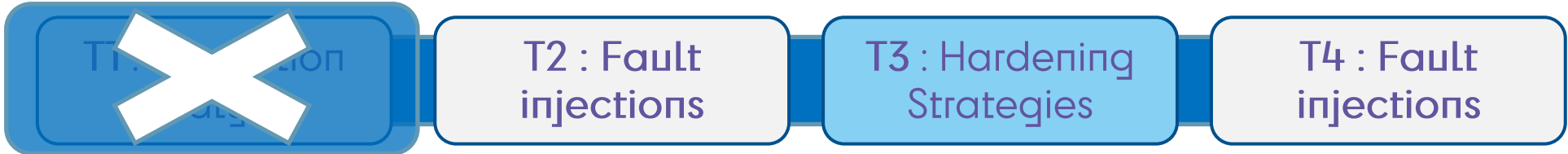


As expert in radiation experiments with a strong knowledge on testing complex components

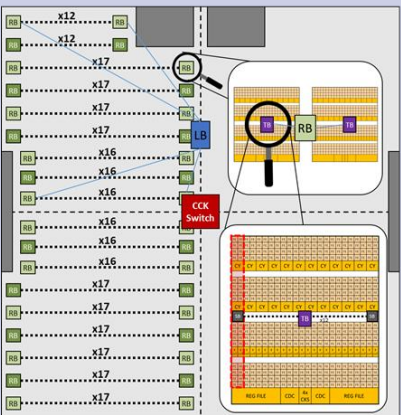


NUCLETUDES AS COORDINATOR OF FAULT INJECTIONS EXP.

Tasks list overview:



- Designing elementary tests on the targeted FPGAs
→ Ex: Rare but critical events requiring high flux

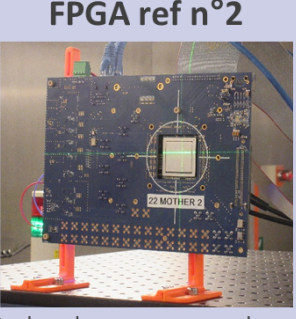
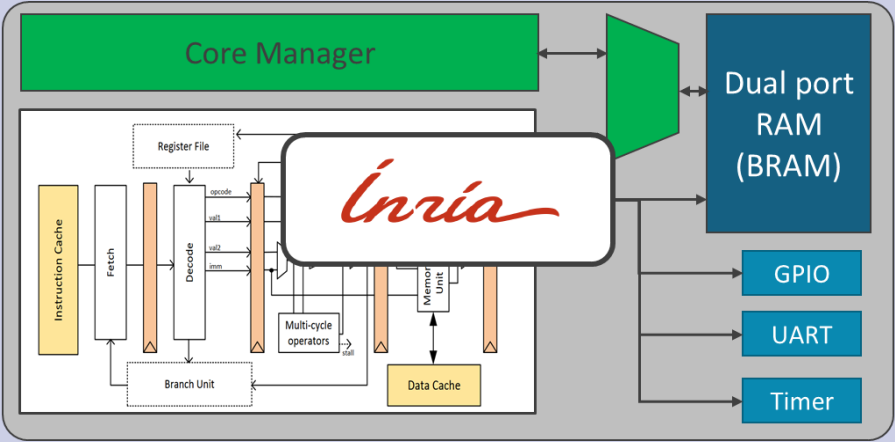


Experimental data feedback for MUSCA SEP3 and TERRIFIC simulation tools on the UCL-NIF Facility

- Porting a RISC-V IP (Comet-V) for fault injections
→ Comparing 2 FPGA : NX & state of the art flash based FPGA



FPGA ref n°1
Hybrid test board (modified)
→ ULTRA300 from NX



FPGA ref n°2
Nucleudes neutron test board
→ Other FPGA (not NX)



Functionality requests and user feedback for a wider adoption of the Comet-V core



User feedback on Impulse toolchain

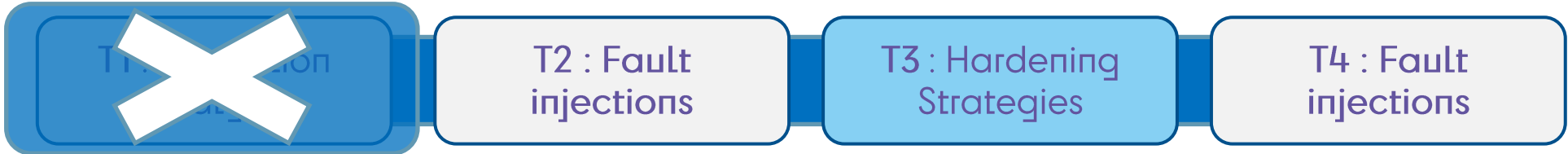
Support for adding RISC-V IP in NX libs

Complete & compare radiation data

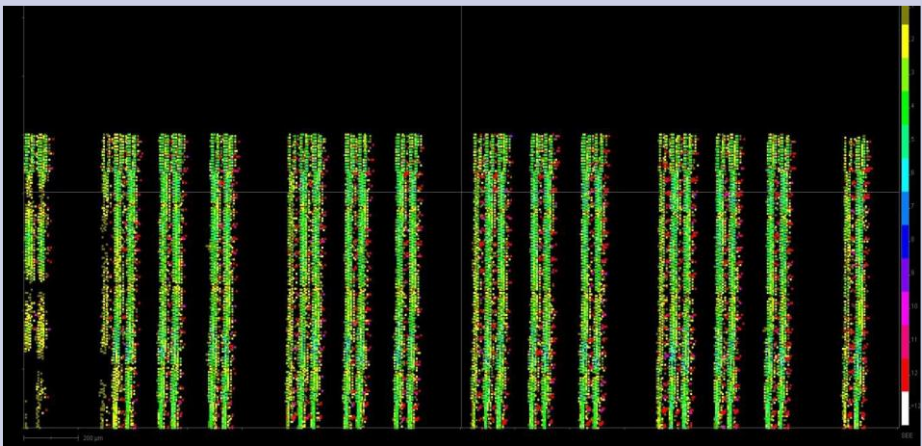
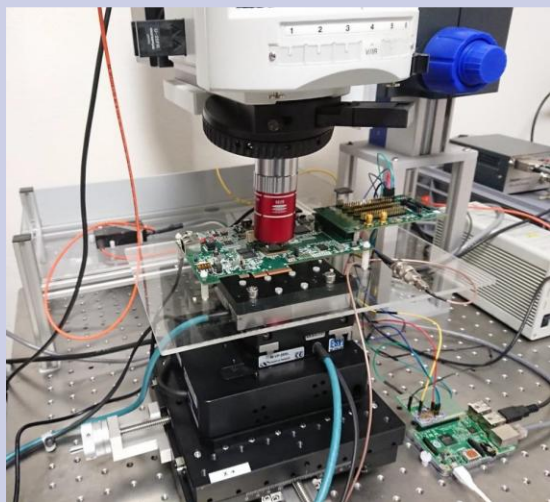


NUCLETUDES AS SUPPORT FOR HARDENING STRATEGIES

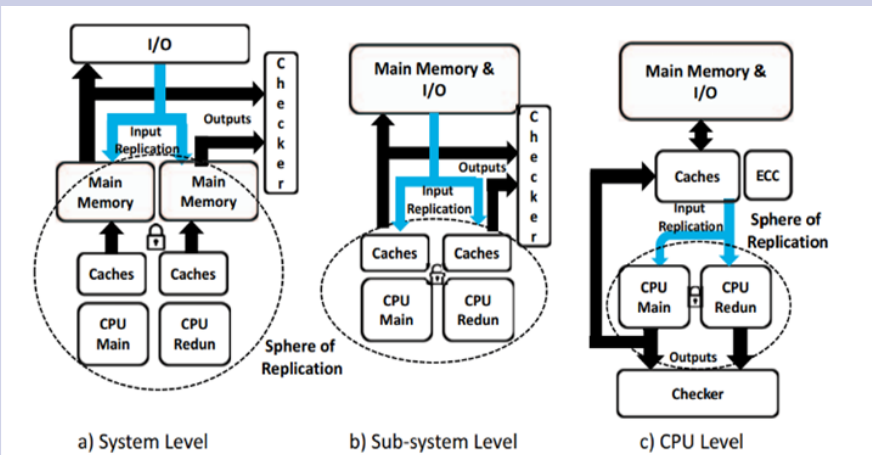
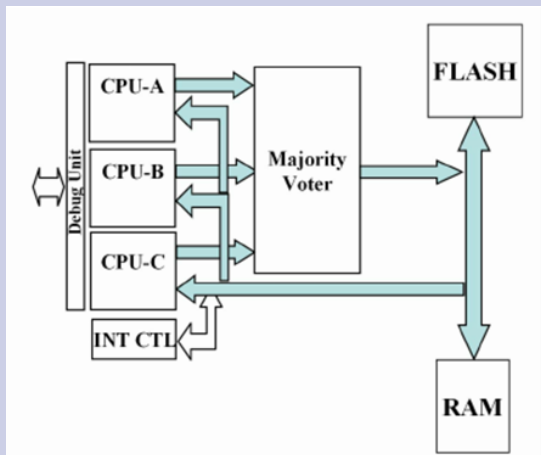
Tasks list overview:



- **Dedicated fault injection test methods**
→ SPA laser to accurately identify critical events & test mitigations



- **Support for RISC-V hardening techniques**
→ TMR, Cores Lock stepping, ECC, CRAM scrubbing, ...



User feedback on
Impulse toolchain

Support for adding
a fault tolerant
RISC-V IP in NX Libs

Support for identifying
key resources requiring
hardening



Inria

Support to identify vulnerable
parts
of the Comet-V core

Support to select the most
suitable hardening methods

FOCH global Presentation

20/11/2025
9h20-9h50

—
Refectoire



JOSEPH
PATUREL Inria



**Development of a fault-
tolerant IP and evaluation of FPGA
SRAM with tests in a highly radiative
environment**

Partner Presentation

Inria



TARAN team, Domain-Specific Computers in the post Moore's law era

- About 40 members, researchers, engineers and PhD students
- Automatically create hardware that is resilient, computes just right and leverages emerging technologies

Research direction: Resilient accelerators, CPUs and GPUs

- Vulnerability analysis at Design-time and Run-time, task-level scheduling strategies, exploring low-overhead techniques to protect architectures against faults (and attacks).

Building around the RISC-V ecosystem and open-source hardware

- Member of the RISC-V foundation
- Maintainer of the Comet core



- Cross-layer vulnerability analysis of NanoXplore FPGA fabric
 - Provide a fault-tolerant RISC-V processor IP

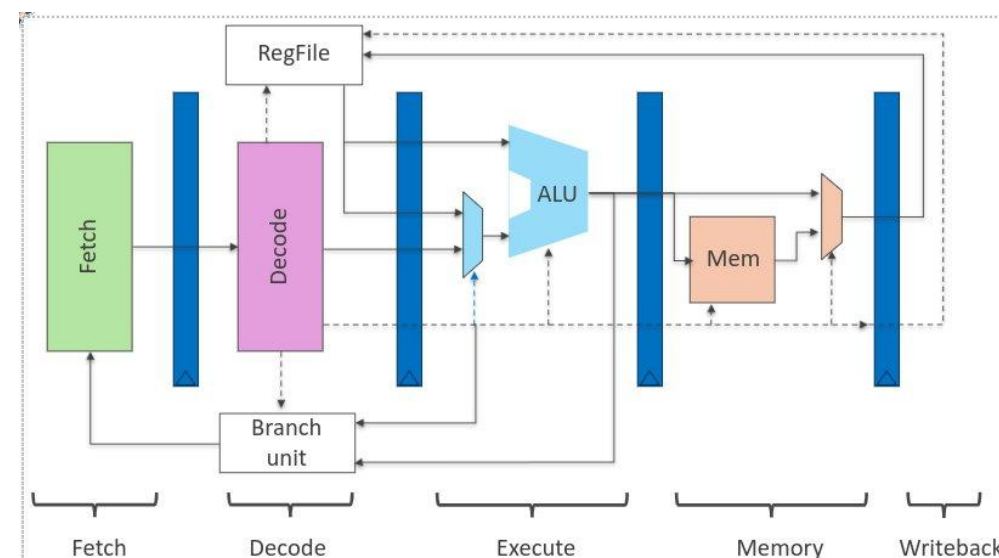


RISC-V Evaluation Platform

Comet^[1]

Embedded class in-order, 5-stage pipelined RISC-V 32-bit core written in C++

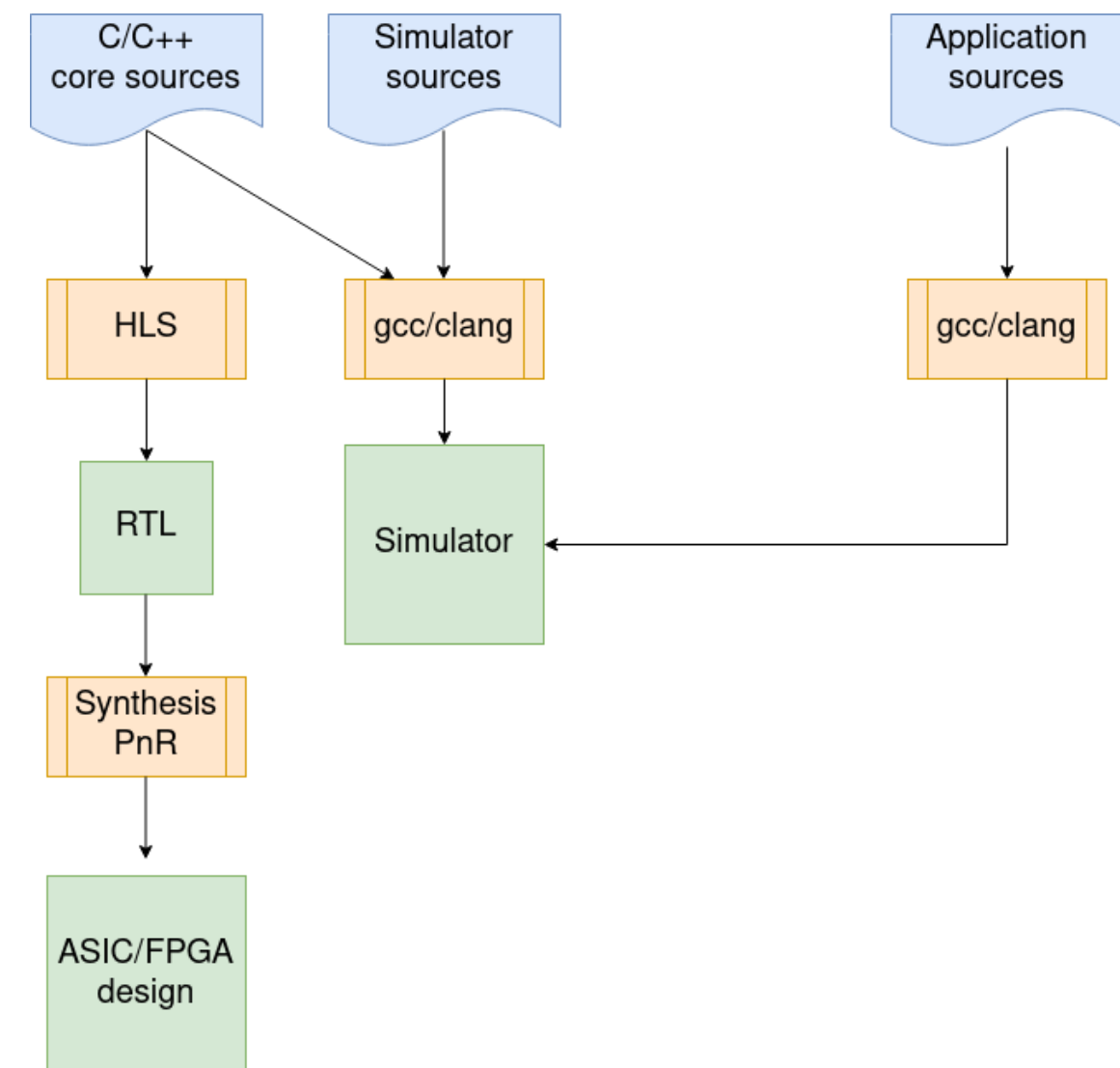
- M-extension, caches and standard IRQ support
- Easily modified using open-source and industry-standard tools



Used as a test platform for microarchitectural research:

- Dependability^[2], Security^[3], Normally-Off Computing^[4]

Developped an FPGA SoC around the core for beam-testing in tandem with Nuclétudes



[1]: S. Rokicki, D. Pala, J. Paturel and O. Sentieys, "What You Simulate Is What You Synthesize: Designing a Processor Core from C++ Specifications", IEEE/ACM ICCAD 2019

[2]: P. R. Nikiema et al., "Towards Dependable RISC-V Cores for Edge Computing Devices," IEEE IOLTS 2023

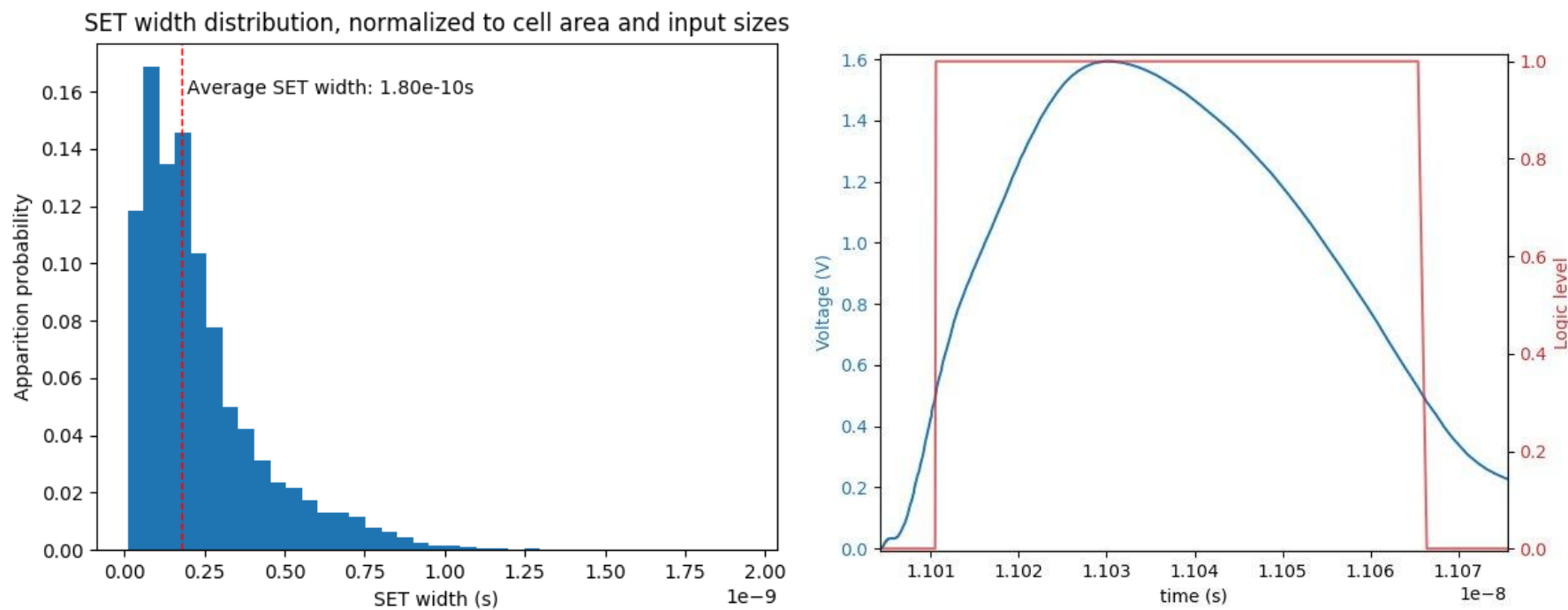
[3]: L. Savary, S. Rokicki and S. Derrien, "Ahead of Time Generation for GPSA Protection in RISC-V Embedded Cores", IEEE ASAP 2025

[4]: D. Pala, I. Miro-Panades and O. Sentieys, "Freezer: A Specialized NVM Backup Controller for Intermittently Powered Systems," in IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems 2021



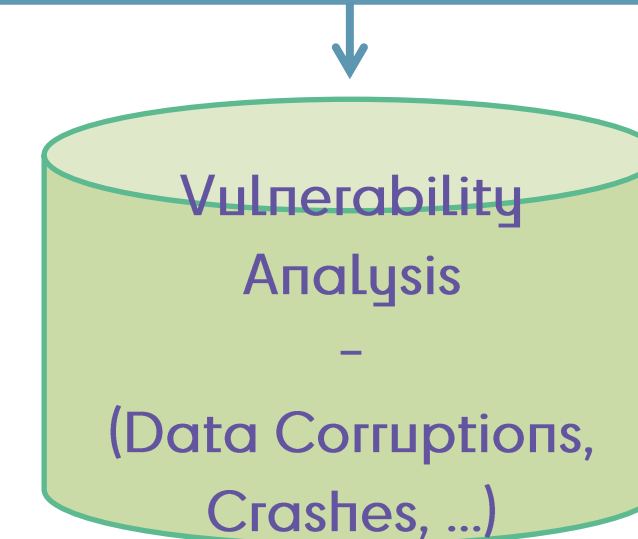
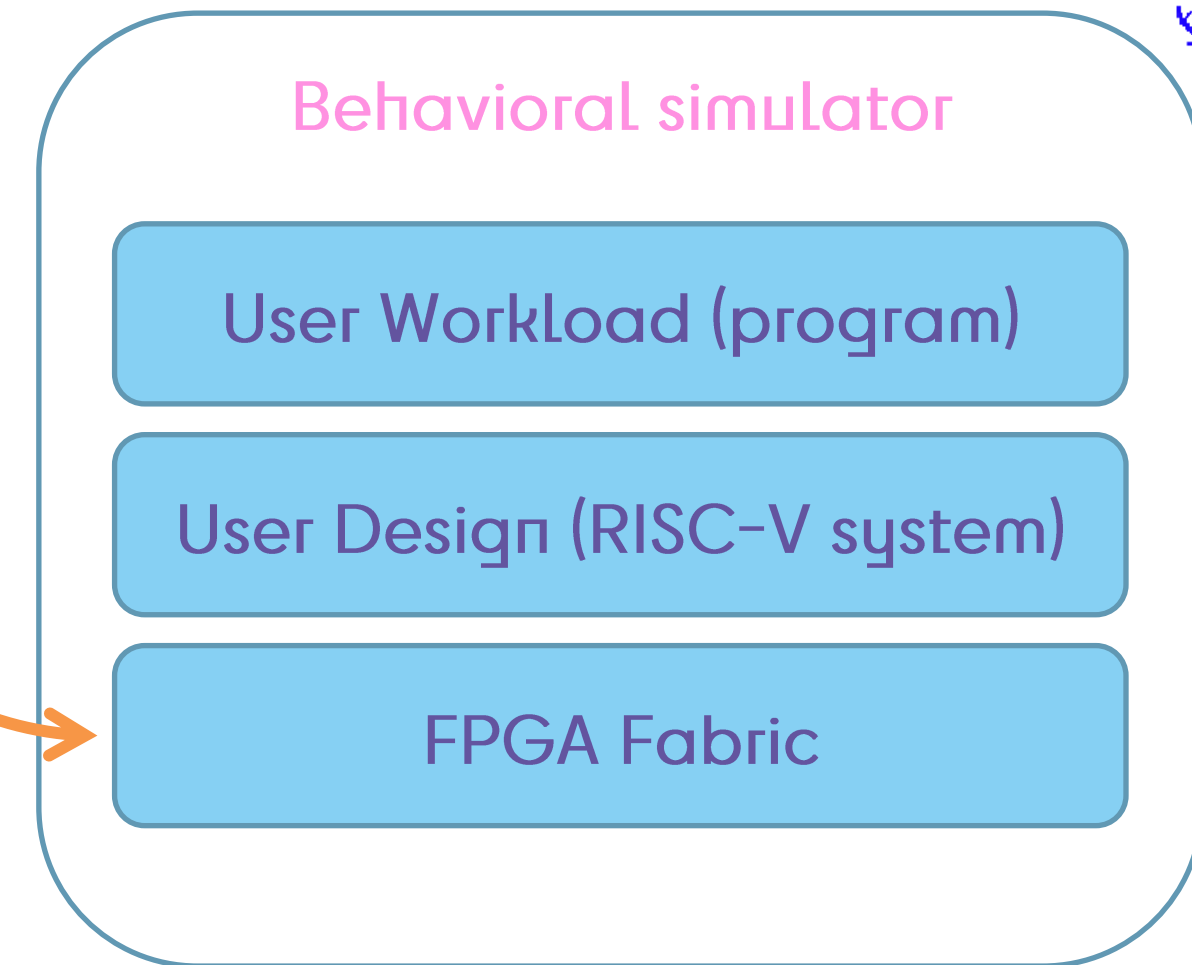
Gate-Level Fault Injection

Inject fault profiles provided by Onera in a full-fabric simulation



Allows us to efficiently guide selective hardening of:

- Software that is running on the core
- The CPU microarchitecture: ECC register file, lockstep cores, etc.
- The FPGA fabric: redundant routing paths, scrubbing strategies, etc.





- First test campaign: 23/12/2025





**Thank
you**